

Selected Publications 2010

Kawai, S.; Glatzel, T.; Hug, H. J.; Meyer, E. Atomic contact potential variations of Si(111)-7 × 7 analyzed by Kelvin probe force microscopy. *Nanotechnology* 2010, 21 (24), 245704 (9 pp.).

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Parschau, M.; Hug, H. J.; Rieder, K. H.; Ernst, K. H. Hopping, turning and flipping of single molecules during lateral manipulation with a scanning tunneling microscope. *Surf. Interface Anal.* 2010, 42 (10-11), 1629-1633. <https://doi.org/10.1002/sia.3574>

Pignedoli, C. A.; Passerone, D.; Hug, H. J.; Pélisson-Schecker, A.; Patscheider, J. Role of negatively charged defects in the lattice contraction of Al-Si-N. *Appl. Phys. Lett.* 2010, 96 (7), 071908 (3 pp.).

<https://doi.org/10.1063/1.3323093>

Pélisson-Schecker, A.; Hug, H. J.; Patscheider, J. Complex phase compositions in nanostructured coatings as evidenced by photoelectron spectroscopy: the case of Al-Si-N hard coatings. *J. Appl. Phys.* 2010, 108 (2), 023508 (8 pp.). <https://doi.org/10.1063/1.3460099>

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